

<b>Notice of References Cited</b>	Application/Control No. 10/707,112	Applicant(s)/Patent Under Reexamination LO ET AL.	
	Examiner Lynne A. Gurley	Art Unit 2812	Page 1 of 1

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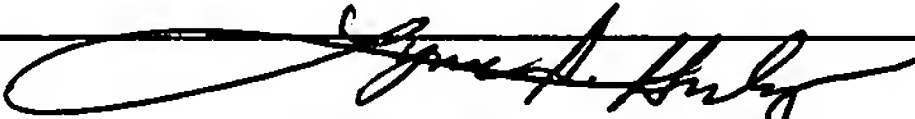
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NON-PATENT DOCUMENTS

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	U	Wolf et al. , Silicon Processing for the VLSI Era, Vol I, Lattice Press, 1986, pp. 166-174, 182-195
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**TC 2800, AU 2812**

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.